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Volume 46, Issue 11, Part 1, Nov. 1998 Page(s):1679 - 1685
Digital Object Identifier 10.1109/22.734558

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6. **Extracting a polynomial ac FET model with thermal couplings from S-parameter measureme**
   Vuolevi, J.; Rahkonen, T.;
   Circuits and Systems, 2001. ISCAS 2001. The 2001 IEEE International Symposium on
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   Digital Object Identifier 10.1109/ISCAS.2001.921347

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7. **A robust high voltage Si LDMOS model extraction process to achieve first pass linear RFIC a**
   success
   Pla, J.A.; Bridges, D.;
   Radio Frequency Integrated Circuits (RFIC) Symposium, 2002 IEEE
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   Digital Object Identifier 10.1109/RFIC.2002.1012064

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   Microwave Symposium Digest, 2004 IEEE MTT-S International
   Volume 1, 6-11 June 2004 Page(s):39 - 42 Vol.1
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    Electronic Components and Technology Conference, 2001. Proceedings., 51st
    29 May-1 June 2001 Page(s):715 - 720
    Digital Object Identifier 10.1109/ECTC.2001.927811

    AbstractPlus | Full Text: PDF(1248 KB)   **IEEE CNF**
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    Karray, M.; Desgreys, P.; Charlot, J.-J.;
    Industrial Technology, 2003 IEEE International Conference on
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    Digital Object Identifier 10.1109/ICIT.2003.1290750

    AbstractPlus | Full Text: PDF(1352 KB)   **IEEE CNF**
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    Quere, R.; Teyssier, J.P.; Viaud, J.P.; Obregon, J.;
    Integrated Nonlinear Microwave and Millimeterwave Circuits, 1994. Third International Workshop on
    5-7 Oct. 1994 Page(s):27 - 41
    Digital Object Identifier 10.1109/INMMC.1994.512511

    AbstractPlus | Full Text: PDF(1016 KB)   **IEEE CNF**

☐ **13. A new large-signal model based on pulse measurement techniques for RF power MOSFET**
Collantes, J.M.; Raoux, J.J.; Villotte, J.P.; Quere, R.; Montoriol, G.; Dupis, F.;
Microwave Symposium Digest, 1995., IEEE MTT-S International
16-20 May 1995 Page(s):1553 - 1556 vol.3
Digital Object Identifier 10.1109/MWSYM.1995.406271

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Gao Xuebang; Guo Binghui;
Microwave and Millimeter Wave Technology Proceedings, 1998. ICMMT '98. 1998 International Co
18-20 Aug. 1998 Page(s):116 - 119
Digital Object Identifier 10.1109/ICMMT.1998.768240

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☐ **15. An optimized method for computer-aided DC measurements of power MOS transistors**
Gracia, J.; Aranceta, F.J.;
Instrumentation and Measurement, IEEE Transactions on
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Digital Object Identifier 10.1109/19.7462

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☐ **16. Improvements in three-terminal thermoconverter technique**
Bergeest, R.; Chatzopoulos, Z.; Grno, L.; Ihlenfeld, W.G.; Lalinsky, T.; Kuzmik, J.;
Precision Electromagnetic Measurements Digest, 1996 Conference on
17-21 June 1996 Page(s):564
Digital Object Identifier 10.1109/CPEM.1996.547350

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Parker, A.E.; Rathmell, J.G.;
Microwave Theory and Techniques, IEEE Transactions on
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Digital Object Identifier 10.1109/TMTT.2005.850399

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Thermal and Thermomechanical Phenomena in Electronic Systems, 2004. ITHERM '04. The Ninth Conference on
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Batty, W.; Christoffersen, C.E.; Panks, A.J.; David, S.; Snowden, C.M.; Steer, M.B.;
Components and Packaging Technologies, IEEE Transactions on [see also Components, Packagin Technology, Part A: Packaging Technologies, IEEE Transactions on]
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Digital Object Identifier 10.1109/6144.974944

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☐ 3. **Global electrothermal CAD of complex nonlinear 3-D systems based on a fully physical time thermal model**
Batty, W.; Christoffersen, C.E.; David, S.; Panks, A.J.; Johnson, R.G.; Snowden, C.M.; Steer, M.B.;
Microwave Symposium Digest, 2001 IEEE MTT-S International
Volume 2, 20-25 May 2001 Page(s):667 - 670 vol.2
Digital Object Identifier 10.1109/MWSYM.2001.966982

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Digital Object Identifier 10.1109/STHERM.2005.1412189

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Ibrahim, M.S.; Paradis, L.R.; Paterson, D.;
<u>Semiconductor Thermal Measurement and Management Symposium, 1991, SEMI-THERM VII, Pro</u>
<u>Annual IEEE</u>
12-14 Feb. 1991 Page(s):80 - 85
Digital Object Identifier 10.1109/STHERM.1991.152917

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Ibrahim, M.S.; Paradis, L.R.; Paterson, D.;
<u>Components, Hybrids, and Manufacturing Technology, IEEE Transactions on [see also IEEE Trans</u>
<u>Packaging, and Manufacturing Technology, Part A, B, C]</u>
Volume 15, Issue 5, Oct. 1992 Page(s):723 - 729
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8. **A symmetric and thermally de-embedded nonlinear FET model for wireless and microwave a**
Wood, J.; Root, D.E.;
<u>Microwave Symposium Digest, 2004 IEEE MTT-S International</u>
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Digital Object Identifier 10.1109/MWSYM.2004.1335791

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9. **Dynamical model for GaAs optical FETs in 0-120°C temperature range**
Ramovic, R.; Andrin, R.; Grbovic, D.;
<u>Microelectronics, 1997. Proceedings., 1997 21st International Conference on</u>
Volume 2, 14-17 Sept. 1997 Page(s):493 - 496 vol.2
Digital Object Identifier 10.1109/ICMEL.1997.632876

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<u>AbstractPlus</u> | Full Text: <u>PDF</u>(642 KB)   **IEEE CNF**
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11. **Electrothermal model of GaAs FET devices for fast PC implementation**
Pesare, M.; Giorgio, A.; Perri, A.G.;
<u>Circuits, Devices and Systems, IEE Proceedings [see also IEE Proceedings G- Circuits, Devices an</u>
Volume 148, Issue 1, Feb 2001 Page(s):40 - 44
Digital Object Identifier 10.1049/ip-cds:20010173

<u>AbstractPlus</u> | Full Text: <u>PDF</u>(528 KB)   **IEE JNL**

12. **Thermal analysis for improved packaging of 4-channel 42 V/14 V DC/DC converter**
Lee, S.-Y.; Pfaelzer, A.G.; van Wyk, J.D.;
<u>Industry Applications Conference, 2004. 39th IAS Annual Meeting. Conference Record of the 2004</u>
Volume 4, 3-7 Oct. 2004 Page(s):2330 - 2336 vol.4
Digital Object Identifier 10.1109/IAS.2004.1348800

13. **A new physics based dynamic electro thermal large signal model for RF LDMOS FETs**
Versleijen, M.P.J.G.; Bloem, V.J.; van Steenwijk, J.A.; Yanson, O.I.;
Microwave Symposium Digest, 2004 IEEE MTT-S International
Volume 1, 6-11 June 2004 Page(s):39 - 42 Vol.1
Digital Object Identifier 10.1109/MWSYM.2004.1335792

14. **Thermal aspects of GaAs power FET attachment using isotropically conductive adhesive**
Mayer, M.; Nicolics, J.; Hanreich, G.; Mundlein, M.;
Polymers and Adhesives in Microelectronics and Photonics, 2002, POLYTRONIC 2002, 2nd Interna
Conference on
23-26 June 2002 Page(s):38 - 43
Digital Object Identifier 10.1109/POLYTR.2002.1020180

15. **A robust high voltage Si LDMOS model extraction process to achieve first pass linear RFIC a success**
Pla, J.A.; Bridges, D.;
Microwave Symposium Digest, 2002 IEEE MTT-S International
Volume 1, 2-7 June 2002 Page(s):263 - 266
Digital Object Identifier 10.1109/MWSYM.2002.1011607

16. **Empirical modeling of low-frequency dispersive effects due to traps and thermal phenomena**
Filicori, F.; Vannini, G.; Santarelli, A.; Sanchez, A.M.; Tazon, A.; Newport, Y.;
Microwave Theory and Techniques, IEEE Transactions on
Volume 43, Issue 12, Part 2, Dec. 1995 Page(s):2972 - 2981
Digital Object Identifier 10.1109/22.475663

17. **Analytical approach to evaluate thermal reduction effects of peripheral structures on microw device chips**
Yanagawa, S.;
Microwave and Wireless Components Letters, IEEE [see also IEEE Microwave and Guided Wave L
Volume 15, Issue 5, May 2005 Page(s):324 - 326
Digital Object Identifier 10.1109/LMWC.2005.847693

18. **Extracting a polynomial ac FET model with thermal couplings from S-parameter measureme**
Vuolevi, J.; Rahkonen, T.;
Circuits and Systems, 2001, ISCAS 2001. The 2001 IEEE International Symposium on
Volume 3, 6-9 May 2001 Page(s):461 - 464 vol. 2
Digital Object Identifier 10.1109/ISCAS.2001.921347

19. **A robust high voltage Si LDMOS model extraction process to achieve first pass linear RFIC a success**
Pla, J.A.; Bridges, D.;
Radio Frequency Integrated Circuits (RFIC) Symposium, 2002 IEEE
2-4 June 2002 Page(s):347 - 350

Digital Object Identifier 10.1109/RFIC.2002.1012064

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□ 20. **A functional GaAs FET noise model**
Podell, A.F.;
Electron Devices, IEEE Transactions on
Volume 28, Issue 5, May 1981 Page(s):511 - 517

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□ 21. **Nonlinear-dispersive GaAs FET drain-current model for harmonic balance simulation**
Eccleston, K.W.;
Microwave Conference Proceedings, 1997. APMC '97., 1997 Asia-Pacific
2-5 Dec. 1997 Page(s):717 - 720 vol.2
Digital Object Identifier 10.1109/APMC.1997.654642

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□ 22. **A new extraction method for the two-parameter FET temperature noise model**
Garcia, M.; Stenarson, J.; Yhland, K.; Zirath, H.; Angelov, I.;
Microwave Theory and Techniques, IEEE Transactions on
Volume 46, Issue 11, Part 1, Nov. 1998 Page(s):1679 - 1685
Digital Object Identifier 10.1109/22.734558

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29 May-1 June 2001 Page(s):715 - 720
Digital Object Identifier 10.1109/ECTC.2001.927811

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□ 24. **Temperature distribution in power GaAs field effect transistors using spatially resolved phot**
mapping
Landesman, J.P.; Martin, E.; Braun, P.;
Physical and Failure Analysis of Integrated Circuits, 1999. Proceedings of the 1999 7th Internationa
5-9 July 1999 Page(s):185 - 190
Digital Object Identifier 10.1109/IPFA.1999.791331

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□ 25. **Measurement based nonlinear electrothermal modeling of GaAs FET with dynamical trappin**
Ouarch, Z.; Collantes, J.M.; Teyssier, J.P.; Quere, R.;
Microwave Symposium Digest, 1998 IEEE MTT-S International
Volume 2, 7-12 June 1998 Page(s):599 - 602 vol.2
Digital Object Identifier 10.1109/MWSYM.1998.705064

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Circuits and Systems, 2001. MWSCAS 2001. Proceedings of the 44th IEEE 2001 Midwest Sympos
Volume 2, 14-17 Aug. 2001 Page(s):768 - 772 vol.2
Digital Object Identifier 10.1109/MWSCAS.2001.986300

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Jianjun Xu; Yagoub, M.C.E.; Runtao Ding; Qi Jun Zhang;
Microwave Theory and Techniques, IEEE Transactions on
Volume 51, Issue 1, Part 1, Jan. 2003 Page(s):226 - 237
Digital Object Identifier 10.1109/TMTT.2002.806910

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☐ 3. **An empirical table-based FET model**
Angelov, I.; Rorsman, N.; Stenarson, J.; Garcia, M.; Zirath, H.;
Microwave Theory and Techniques, IEEE Transactions on
Volume 47, Issue 12, Dec. 1999 Page(s):2350 - 2357
Digital Object Identifier 10.1109/22.808981

AbstractPlus | References | Full Text: PDF(252 KB)   **IEEE JNL**
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☐ 4. **An empirical-table based FET model**
Angelov, I.; Rorsman, N.; Stenarson, J.; Garcia, M.; Zirath, H.;
Microwave Symposium Digest, 1999 IEEE MTT-S International
Volume 2, 13-19 June 1999 Page(s):525 - 528 vol.2
Digital Object Identifier 10.1109/MWSYM.1999.779816

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☐ 5. **Dynamically configurable pHEMT model using neural networks for CAD**
Davis, B.; White, C.; Reece, M.A.; Bayne, M.E., Jr.; Thompson, W.L., II; Richardson, N.L.; Walker, L
Microwave Symposium Digest, 2003 IEEE MTT-S International
Volume 1, 8-13 June 2003 Page(s):177 - 180 vol.1

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   Microwave Theory and Techniques, IEEE Transactions on
   Volume 43, Issue 12, Part 2, Dec. 1995 Page(s):2972 - 2981
   Digital Object Identifier 10.1109/22.475663

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7. **A new empirical model for GaAs FET in nonlinear circuit simulation**
   Cao, J.; Lin, F.; Kooi, P.S.; Leong, M.S.;
   Microwave Conference Proceedings, 1997. APMC '97, 1997 Asia-Pacific
   2-5 Dec. 1997 Page(s):517 - 520 vol.2
   Digital Object Identifier 10.1109/APMC.1997.654592

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8. **Construct GaAs FET DC model from drain-port DC power and conductance**
   Liu, L.; Lin, F.; Kooi, P.S.; Leong, M.S.;
   Microwave Conference, 1999 Asia Pacific
   Volume 1, 30 Nov.-3 Dec. 1999 Page(s):56 - 59 vol.1
   Digital Object Identifier 10.1109/APMC.1999.828047

   AbstractPlus | Full Text: PDF(136 KB)   **IEEE CNF**
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9. **A table lookup FET model for accurate analog circuit simulation**
   Rofougaran, A.; Abidi, A.A.;
   Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on
   Volume 12, Issue 2, Feb. 1993 Page(s):324 - 335
   Digital Object Identifier 10.1109/43.205011

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10. **A 110 GHz scalable FET model based on 50 GHz S-parameter measurements**
    Cidronali, A.; Collodi, G.; Santarelli, A.; Vannini, G.;
    Microwave Symposium Digest., 2000 IEEE MTT-S International
    Volume 3, 11-16 June 2000 Page(s):1377 - 1380 vol.3
    Digital Object Identifier 10.1109/MWSYM.2000.861797

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11. **On wafer intermodulation distortion measurements on resistive FET mixers for device comp validation**
    Hutabarat, M.T.; Webster, D.R.; Haigh, D.G.; Schreurs, D.; van der Zanden, K.; Edgar, D.L.; Borsos Thayne, I.G.; Parker, A.E.;
    High Performance Electron Devices for Microwave and Optoelectronic Applications, 1999. EDMO. 1
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    Digital Object Identifier 10.1109/EDMO.1999.821480

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12. **A new empirical large signal model for silicon RF LDMOS FETs**
    Miller, M.; Dinh, T.; Shumate, E.;
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    23-26 Feb. 1997 Page(s):19 - 22
    Digital Object Identifier 10.1109/MTTTWA.1997.595103

    AbstractPlus | Full Text: PDF(328 KB)   **IEEE CNF**

☐ **13. An accurate dc model of 2-DEG FET for implementation on a circuit simulator**
Hida, H.; Itoh, T.; Ohata, K.;
Electron Device Letters, IEEE
Volume 7, Issue 6, Jun 1986 Page(s):393 - 395

AbstractPlus | Full Text: PDF(296 KB)   **IEEE JNL**

☐ **14. Millimeter-wave FET modeling using on-wafer measurements and EM simulation**
Cidronali, A.; Collodi, G.; Santarelli, A.; Vannini, G.; Manes, G.;
Microwave Theory and Techniques, IEEE Transactions on
Volume 50, Issue 2, Feb. 2002 Page(s):425 - 432
Digital Object Identifier 10.1109/22.982219

AbstractPlus | References | Full Text: PDF(218 KB)   **IEEE JNL**

☐ **15. An improved large-signal model for varactor and GaAs FET diodes**
Gao Xuebang; Liang Yaping; Liao Bin;
Microwave Conference Proceedings, 1997. APMC '97, 1997 Asia-Pacific
2-5 Dec. 1997 Page(s):729 - 732 vol.2
Digital Object Identifier 10.1109/APMC.1997.654645

AbstractPlus | Full Text: PDF(184 KB)   **IEEE CNF**

☐ **16. An improved FET model for computer simulators**
Parker, A.E.; Skellern, D.J.;
Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on
Volume 9, Issue 5, May 1990 Page(s):551 - 553
Digital Object Identifier 10.1109/43.55175

AbstractPlus | Full Text: PDF(192 KB)   **IEEE JNL**

☐ **17. A new approach to FET model scaling and MMIC design based on electromagnetic analysis**
Cidronali, A.; Collodi, G.; Vannini, G.; Santarelli, A.;
Microwave Theory and Techniques, IEEE Transactions on
Volume 47, Issue 6, Part 2, June 1999 Page(s):900 - 907
Digital Object Identifier 10.1109/22.769324

AbstractPlus | References | Full Text: PDF(252 KB)   **IEEE JNL**

☐ **18. Semi-empirical SPICE models for carbon nanotube FET logic**
Dwyer, C.; Cheung, M.; Sorin, D.J.;
Nanotechnology, 2004. 4th IEEE Conference on
16-19 Aug. 2004 Page(s):386 - 388
Digital Object Identifier 10.1109/NANO.2004.1392359

AbstractPlus | Full Text: PDF(558 KB)   **IEEE CNF**

☐ **19. Modeling the drain current of the dual-gate GaAs MESFET**
Ibrahim, M.; Syrett, B.; Bennett, J.;
Microwave Symposium Digest, 2003 IEEE MTT-S International
Volume 3, 8-13 June 2003 Page(s):2113 - 2116 vol.3

AbstractPlus | Full Text: PDF(299 KB)   **IEEE CNF**

☐ **20.**
A balanced Ka-Band GaAs FET MMIC frequency doubler
Abdo-Tuko, M.; Bertenburg, R.; Wolff, L.;

Microwave and Guided Wave Letters. IEEE [see also IEEE Microwave and Wireless Components L
Volume 4, Issue 7, July 1994 Page(s):217 - 219
Digital Object Identifier 10.1109/75.298245

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21. Analytical analysis of noise figures in FET resistive mixers
Won Ko; Youngwoo Kwon;
Electronics Letters
Volume 35, Issue 14, 8 Jul 1999 Page(s):1169 - 1170
Digital Object Identifier 10.1049/el:19990791

AbstractPlus | Full Text: PDF(216 KB) **IEE JNL**

22. A two-dimensional numerical FET model for DC, AC, and large-signal analysis
Reiser, M.;
Electron Devices. IEEE Transactions on
Volume 20, Issue 1, Jan 1973 Page(s):35 - 45

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23. Hot-carrier effects in MOSFET's with nitrided-oxide gate-dielectrics prepared by rapid therma
Hori, T.; Yasui, T.; Akamatsu, S.;
Electron Devices. IEEE Transactions on
Volume 39, Issue 1, Jan. 1992 Page(s):134 - 147
Digital Object Identifier 10.1109/16.108222

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24. Low-Noise Low-Distortion GaAs FET Amplifiers for 6 GHz Single Sideband Radio
Agarwal, K.K.; Kuo, Y.L.;
Microwave Symposium Digest. MTT-S International
Volume 78, Issue 1, Jun 1978 Page(s):393 - 395

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25. Investigation of the physical mechanisms governing the performance of OEIC-compatible p-lateral injection lasers
Sargent, E.H.; Xu, J.M.;
Lasers and Electro-Optics Society Annual Meeting. 1996. LEOS 96., IEEE
Volume 1, 18-19 Nov. 1996 Page(s):314 - 315 vol.1
Digital Object Identifier 10.1109/LEOS.1996.565258

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Digital Object Identifier 10.1109/MWSCAS.2001.986300

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☐ 2. **Exact adjoint sensitivity analysis for neural-based microwave modeling and design**
Jianjun Xu; Yagoub, M.C.E.; Runtao Ding; Qi Jun Zhang;
Microwave Theory and Techniques, IEEE Transactions on
Volume 51, Issue 1, Part 1, Jan. 2003 Page(s):226 - 237
Digital Object Identifier 10.1109/TMTT.2002.806910

AbstractPlus | References | Full Text: PDF(661 KB)   **IEEE JNL**
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☐ 3. **An empirical table-based FET model**
Angelov, I.; Rorsman, N.; Stenarson, J.; Garcia, M.; Zirath, H.;
Microwave Theory and Techniques, IEEE Transactions on
Volume 47, Issue 12, Dec. 1999 Page(s):2350 - 2357
Digital Object Identifier 10.1109/22.808981

AbstractPlus | References | Full Text: PDF(252 KB)   **IEEE JNL**
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☐ 4. **An empirical-table based FET model**
Angelov, I.; Rorsman, N.; Stenarson, J.; Garcia, M.; Zirath, H.;
Microwave Symposium Digest, 1999 IEEE MTT-S International
Volume 2, 13-19 June 1999 Page(s):525 - 528 vol.2
Digital Object Identifier 10.1109/MWSYM.1999.779816

AbstractPlus | Full Text: PDF(332 KB)   **IEEE CNF**
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☐ 5. **Dynamically configurable pHEMT model using neural networks for CAD**
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Microwave Symposium Digest, 2003 IEEE MTT-S International
Volume 1, 8-13 June 2003 Page(s):177 - 180 vol.1

☐ 6. **Empirical modeling of low-frequency dispersive effects due to traps and thermal phenomena**
Filicori, F.; Vannini, G.; Santarelli, A.; Sanchez, A.M.; Tazon, A.; Newport, Y.;
Microwave Theory and Techniques, IEEE Transactions on
Volume 43, Issue 12, Part 2, Dec. 1995 Page(s):2972 - 2981
Digital Object Identifier 10.1109/22.475663

AbstractPlus | Full Text: PDF(1000 KB)   **IEEE JNL**
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☐ 7. **A new empirical model for GaAs FET in nonlinear circuit simulation**
Cao, J.; Lin, F.; Kooi, P.S.; Leong, M.S.;
Microwave Conference Proceedings, 1997. APMC '97, 1997 Asia-Pacific
2-5 Dec. 1997 Page(s):517 - 520 vol.2
Digital Object Identifier 10.1109/APMC.1997.654592

AbstractPlus | Full Text: PDF(300 KB)   **IEEE CNF**
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☐ 8. **Construct GaAs FET DC model from drain-port DC power and conductance**
Liu, L.; Lin, F.; Kooi, P.S.; Leong, M.S.;
Microwave Conference, 1999 Asia Pacific
Volume 1, 30 Nov.-3 Dec. 1999 Page(s):56 - 59 vol.1
Digital Object Identifier 10.1109/APMC.1999.828047

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☐ 9. **A table lookup FET model for accurate analog circuit simulation**
Rofougaran, A.; Abidi, A.A.;
Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on
Volume 12, Issue 2, Feb. 1993 Page(s):324 - 335
Digital Object Identifier 10.1109/43.205011

AbstractPlus | Full Text: PDF(960 KB)   **IEEE JNL**
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☐ 10. **A 110 GHz scalable FET model based on 50 GHz S-parameter measurements**
Cidronali, A.; Collodi, G.; Santarelli, A.; Vannini, G.;
Microwave Symposium Digest, 2000 IEEE MTT-S International
Volume 3, 11-16 June 2000 Page(s):1377 - 1380 vol.3
Digital Object Identifier 10.1109/MWSYM.2000.861797

AbstractPlus | Full Text: PDF(348 KB)   **IEEE CNF**
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☐ 11. **On wafer intermodulation distortion measurements on resistive FET mixers for device comp**
validation
Hutabarat, M.T.; Webster, D.R.; Haigh, D.G.; Schreurs, D.; van der Zanden, K.; Edgar, D.L.; Borsos
Thayne, I.G.; Parker, A.E.;
High Performance Electron Devices for Microwave and Optoelectronic Applications, 1999. EDMO. 1
22-23 Nov. 1999 Page(s):170 - 175
Digital Object Identifier 10.1109/EDMO.1999.821480

AbstractPlus | Full Text: PDF(432 KB)   **IEEE CNF**
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☐ 12. **A new empirical large signal model for silicon RF LDMOS FETs**
Miller, M.; Dinh, T.; Shumate, E.;
Wireless Applications Digest, 1997, IEEE MTT-S Symposium on Technologies for
23-26 Feb. 1997 Page(s):19 - 22
Digital Object Identifier 10.1109/MTTTWA.1997.595103

AbstractPlus | Full Text: PDF(328 KB)   **IEEE CNF**

13. **An accurate dc model of 2-DEG FET for implementation on a circuit simulator**
Hida, H.; Itoh, T.; Ohata, K.;
Electron Device Letters, IEEE
Volume 7, Issue 6, Jun 1986 Page(s):393 - 395

AbstractPlus | Full Text: PDF(296 KB)   **IEEE JNL**

14. **Millimeter-wave FET modeling using on-wafer measurements and EM simulation**
Cidronali, A.; Collodi, G.; Santarelli, A.; Vannini, G.; Manes, G.;
Microwave Theory and Techniques, IEEE Transactions on
Volume 50, Issue 2, Feb. 2002 Page(s):425 - 432
Digital Object Identifier 10.1109/22.982219

AbstractPlus | References | Full Text: PDF(218 KB)   **IEEE JNL**

15. **An improved large-signal model for varactor and GaAs FET diodes**
Gao Xuebang; Liang Yaping; Liao Bin;
Microwave Conference Proceedings, 1997. APMC '97., 1997 Asia-Pacific
2-5 Dec. 1997 Page(s):729 - 732 vol.2
Digital Object Identifier 10.1109/APMC.1997.654645

AbstractPlus | Full Text: PDF(184 KB)   **IEEE CNF**

16. **An improved FET model for computer simulators**
Parker, A.E.; Skellern, D.J.;
Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on
Volume 9, Issue 5, May 1990 Page(s):551 - 553
Digital Object Identifier 10.1109/43.55175

AbstractPlus | Full Text: PDF(192 KB)   **IEEE JNL**

17. **A new approach to FET model scaling and MMIC design based on electromagnetic analysis**
Cidronali, A.; Collodi, G.; Vannini, G.; Santarelli, A.;
Microwave Theory and Techniques, IEEE Transactions on
Volume 47, Issue 6, Part 2, June 1999 Page(s):900 - 907
Digital Object Identifier 10.1109/22.769324

AbstractPlus | References | Full Text: PDF(252 KB)   **IEEE JNL**

18. **Semi-empirical SPICE models for carbon nanotube FET logic**
Dwyer, C.; Cheung, M.; Sorin, D.J.;
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16-19 Aug. 2004 Page(s):386 - 388
Digital Object Identifier 10.1109/NANO.2004.1392359

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Microwave Symposium Digest, 2003 IEEE MTT-S International
Volume 3, 8-13 June 2003 Page(s):2113 - 2116 vol.3

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20. **A balanced Ka-Band GaAs FET MMIC frequency doubler**
Abdo-Tuko, M.; Bertenburg, R.; Wolff, L.;

Microwave and Guided Wave Letters, IEEE [see also IEEE Microwave and Wireless Components L
Volume 4, Issue 7, July 1994 Page(s):217 - 219
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    Won Ko; Youngwoo Kwon;
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    Volume 35, Issue 14, 8 Jul 1999 Page(s):1169 - 1170
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    AbstractPlus | Full Text: PDF(216 KB)   **IEE JNL**

22. **A two-dimensional numerical FET model for DC, AC, and large-signal analysis**
    Reiser, M.;
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    AbstractPlus | Full Text: PDF(1192 KB)   **IEEE JNL**
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23. **Hot-carrier effects in MOSFET's with nitrided-oxide gate-dielectrics prepared by rapid therma**
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    lateral injection lasers
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    Volume 1, 18-19 Nov. 1996 Page(s):314 - 315 vol.1
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      Multitopic Conference, 2004. Proceedings of INMIC 2004, 8th International
      24-26 Dec. 2004 Page(s):669 - 673
      Digital Object Identifier 10.1109/INMIC.2004.1492972

      AbstractPlus | Full Text: PDF(246 KB)   **IEEE CNF**
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      Digital Object Identifier 10.1109/16.259628

      AbstractPlus | Full Text: PDF(224 KB)   **IEEE JNL**
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      Gummel-Poon BJT models
      Chang, C.; Asbeck, P.; Zampardi, P.; Wang, K.C.;
      Microwave Theory and Techniques, IEEE Transactions on
      Volume 47, Issue 1, Jan. 1999 Page(s):108 - 110
      Digital Object Identifier 10.1109/22.740092

      AbstractPlus | References | Full Text: PDF(120 KB)   **IEEE JNL**
      Rights and Permissions

☐ 4. **Silicon BJT modeling using VBIC model**
      Huang, G.W.; Chen, K.M.; Kuan, J.F.; Deng, Y.M.; Wen, S.Y.; Chiu, D.Y.; Wang, M.T.;
      Microwave Conference, 2001. APMC 2001. 2001 Asia-Pacific
      Volume 1, 3-6 Dec. 2001 Page(s):240 - 243 vol.1
      Digital Object Identifier 10.1109/APMC.2001.985631

      AbstractPlus | Full Text: PDF(269 KB)   **IEEE CNF**
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      Moselhy, A.M.; Fouad, M.;
      Radio Science Conference, 1996. NRSC '96., Thirteenth National
      19-21 March 1996 Page(s):517 - 525
      Digital Object Identifier 10.1109/NRSC.1996.551141

AbstractPlus | Full Text: PDF(372 KB)   IEEE CNF
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6. **Design of a broadband microwave BJT active inductor circuit**
    Campbell, C.F.; Weber, R.J.;
    Circuits and Systems, 1991., Proceedings of the 34th Midwest Symposium on
    14-17 May 1991 Page(s):407 - 409 vol.1
    Digital Object Identifier 10.1109/MWSCAS.1991.252183

    AbstractPlus | Full Text: PDF(136 KB)   IEEE CNF
    Rights and Permissions

7. **Compression analysis of a high power BJT amplifier**
    Bandler, J.W.; Biernacki, R.M.; Cai, Q.; Chen, S.H.;
    Integrated Nonlinear Microwave and Millimeterwave Circuits, 1994. Third International Workshop on
    5-7 Oct. 1994 Page(s):173 - 178
    Digital Object Identifier 10.1109/INMMC.1994.512525

    AbstractPlus | Full Text: PDF(308 KB)   IEEE CNF
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8. **Unconditional Stability of a Three-Port Network Characterized with S-Parameters**
    Boehm, J.F.; Albright, W.G.;
    Microwave Theory and Techniques, IEEE Transactions on
    Volume 35, Issue 6, Jun 1987 Page(s):582 - 586

    AbstractPlus | Full Text: PDF(568 KB)   IEEE JNL
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9. **S-parameter measurement prediction for bipolar transistors using a physical device simulato**
    Yuan, J.-S.; Eisenstadt, W.R.;
    Electron Devices, IEEE Transactions on
    Volume 35, Issue 10, Part 1, Oct. 1988 Page(s):1633 - 1639
    Digital Object Identifier 10.1109/16.7365

    AbstractPlus | Full Text: PDF(476 KB)   IEEE JNL
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10. **Improved closed-form expressions for S-parameters of BJTs using modified Gummel-Poon m**
    Nadeem, A.E.; Eisenstadt, W.R.;
    Multi Topic Conference, 2003. INMIC 2003. 7th International
    8-9 Dec. 2003 Page(s):202 - 207
    Digital Object Identifier 10.1109/INMIC.2003.1416697

    AbstractPlus | Full Text: PDF(607 KB)   IEEE CNF
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11. **A simple model for distributed base impedance with AC verification using S-parameter meas**
    Cho, H.; Burk, D.E.;
    Bipolar Circuits and Technology Meeting, 1990., Proceedings of the 1990
    17-18 Sept. 1990 Page(s):106 - 109
    Digital Object Identifier 10.1109/BIPOL.1990.171138

    AbstractPlus | Full Text: PDF(324 KB)   IEEE CNF
    Rights and Permissions

12. **Small-signal and noise model extraction technique for heterojunction bipolar transistor at m frequencies**
    Roux, J.P.; Escotte, L.; Plana, R.; Graffeuil, J.; Delage, S.L.; Blanck, H.;
    Microwave Theory and Techniques, IEEE Transactions on
    Volume 43, Issue 2, Feb. 1995 Page(s):293 - 298
    Digital Object Identifier 10.1109/22.348087

    AbstractPlus | Full Text: PDF(476 KB)   IEEE JNL
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13. **A new large-signal AlGaAs/GaAs HBT model including self-heating effects, with correspondi extraction procedure**
Ke Lu; Perry, P.A.; Brazil, T.J.;
Microwave Theory and Techniques, IEEE Transactions on
Volume 43, Issue 7, Part 1-2, July 1995 Page(s):1433 - 1445
Digital Object Identifier 10.1109/22.392900

AbstractPlus | Full Text: PDF(1124 KB)   IEEE JNL
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14. **A novel cascade-based de-embedding method for on-wafer microwave characterization and measurement**
Ming-Hsiang Cho; Guo-Wei Huang; Kun-Ming Chen; An-Sam Peng;
Microwave Symposium Digest, 2004 IEEE MTT-S International
Volume 2, 6-11 June 2004 Page(s):1237 - 1240 Vol.2
Digital Object Identifier 10.1109/MWSYM.2004.1339212

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15. **A new SPICE-type heterojunction bipolar transistor model for DC, microwave small-signal an circuit simulation**
Ke Lu; Perry, P.; Brazil, T.J.;
Microwave Symposium Digest, 1994., IEEE MTT-S International
23-27 May 1994 Page(s):1579 - 1582 vol.3
Digital Object Identifier 10.1109/MWSYM.1994.335272

AbstractPlus | Full Text: PDF(441 KB)   IEEE CNF
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16. **Characterization and modeling of InGaP HBT low-frequency oscillations**
Burton, R.S.; Dai, P.;
Electron Devices, IEEE Transactions on
Volume 51, Issue 6, June 2004 Page(s):1033 - 1036
Digital Object Identifier 10.1109/TED.2004.829521

AbstractPlus | References | Full Text: PDF(240 KB)   IEEE JNL
Rights and Permissions

17. **Method for BJT transit time evaluation**
Zimmer, T.; Duluc, J.B.; Lewis, N.;
Electronics Letters
Volume 34, Issue 20, 1 Oct. 1998 Page(s):1979 - 1980

AbstractPlus | Full Text: PDF(252 KB)   IEE JNL

18. **Modeling and parameter extraction of BJT substrate resistance**
Tzung-Yin Lee; Fox, R.M.; Green, K.; Vrotsos, T.;
Bipolar/BiCMOS Circuits and Technology Meeting, 1999. Proceedings of the 1999
26-28 Sept. 1999 Page(s):101 - 104
Digital Object Identifier 10.1109/BIPOL.1999.803536

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19. **Application of Test & Measure in Microwave Device Characterization**
Zhanfei Chen; Lingling Sun;
Microwave Conference Proceedings, 2005. APMC 2005. Asia-Pacific Conference Proceedings
Volume 5, 04-07 Dec. 2005 Page(s):1 - 3

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Taeho Kim; Kyounghoon Yang;

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   Guofu Niu; Shiming Zhang; Cressler, J.D.; Joseph, A.J.; Fairbanks, J.S.; Larson, L.E.; Webster, C.S
   Harame, D.L.;
   Electron Devices Meeting, 1999. IEDM Technical Digest. International
   5-8 Dec. 1999 Page(s):573 - 576
   Digital Object Identifier 10.1109/IEDM.1999.824219

   AbstractPlus | Full Text: PDF(340 KB)   IEEE CNF
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22. **Stochastic approach to noise modelling of bipolar microwave transistors**
   Patti, F.; Miceli, V.; Spagnolo, B.;
   High Performance Electron Devices for Microwave and Optoelectronic Applications, 1999. EDMO. 1
   22-23 Nov. 1999 Page(s):236 - 241
   Digital Object Identifier 10.1109/EDMO.1999.821491

   AbstractPlus | Full Text: PDF(312 KB)   IEEE CNF
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23. **Small signal access paths silicon-BJT de-embedding**
   Megherbi, S.; Crozat, P.; Raynaud, G.; Pone, J.-F.;
   Circuits and Systems, 1996. IEEE 39th Midwest symposium on
   Volume 1, 18-21 Aug. 1996 Page(s):277 - 280 vol.1
   Digital Object Identifier 10.1109/MWSCAS.1996.594130

   AbstractPlus | Full Text: PDF(360 KB)   IEEE CNF
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24. **A 2-50 GHz InAlAs/InGaAs-InP HBT distributed amplifier**
   Kobayashi, K.W.; Cowles, J.; Tran, L.T.; Block, T.R.; Oki, A.K.; Streit, D.C.;
   Gallium Arsenide Integrated Circuit (GaAs IC) Symposium, 1996. Technical Digest 1996., 18th Ann
   3-6 Nov. 1996 Page(s):207 - 210
   Digital Object Identifier 10.1109/GAAS.1996.567870

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25. **On-wafer high-frequency measurement improvements**
   Carbonero, J.L.; Joly, R.; Morin, G.; Cabon, B.;
   Microelectronic Test Structures, 1994. ICMTS 1994. Proceedings of the 1994 International Confere
   22-25 March 1994 Page(s):168 - 173
   Digital Object Identifier 10.1109/ICMTS.1994.303482

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